MOSFET – Power, Single N-Channel, μ8FL 30 V, 4.2 mΩ, 71 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C06NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage	V_{DSS}	30	V		
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain Current R _{0.1A}		T _A = 25°C	I _D	21	Α
(Notes 1, 2, 4)		T _A = 100°C		15	
Power Dissipation R _{θJA}		T _A = 25°C	P_{D}	3.1	W
(Note 1, 2, 4)	Steady	T _A = 100°C		1.6	
Continuous Drain Current R _{0JC} (Note 1,	State	T _A = 25°C	I _D	71	
3, 4)		T _A = 100°C		50	Α
Power Dissipation		T _A = 25°C	P_{D}	37	W
R _{θJC} (Note 1, 3, 4)		T _A = 100°C		18	
Pulsed Drain Current	T _A = 25°0	C, t _p = 10 μs	I _{DM}	367	Α
Operating Junction and S	T _J , T _{stg}	–55 to +175	°C		
Source Current (Body Did	I _S	33	Α		
Single Pulse Drain-to-So (T _J = 25°C, I _L = 26 A _{pk} , L	E _{AS}	34	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain) (Notes 1 and 4)	$R_{\theta JC}$	4.1	°C/W
Junction-to-Ambient - Steady State (Notes 1 and 2)	$R_{\theta JA}$	48	0/11

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions
- 2. Surface-mounted on FR4 board using a 650 mm² 2 oz. Cu pad.
- 3. Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

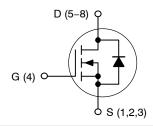


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
30 V	4.2 mΩ @ 10 V	71 A	
	6.1 mΩ @ 4.5 V	///	

N-Channel MOSFET

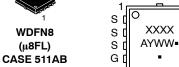




MARKING DIAGRAM

D 5 D D

D



4C06 = Specific Device Code for

NVMTS4C06N

06WF = Specific Device Code of

NVTFS4C06NWF = Assembly Location Α

= Year WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

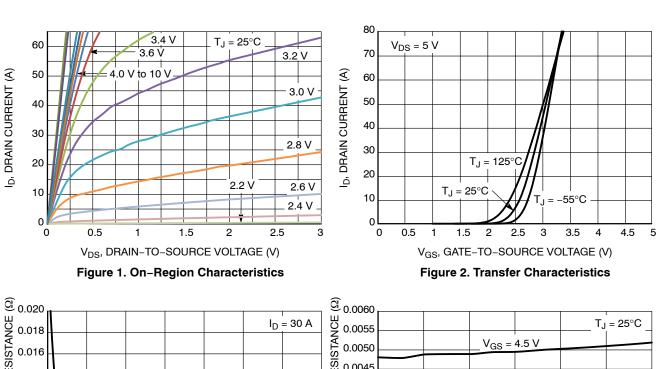
See detailed ordering and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS			_					
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μA		30			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				14.4		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0		
		V _{DS} = 24 V	T _J = 125°C			10	μΑ	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA	
ON CHARACTERISTICS (Note 5)								
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μA	1.3		2.2	V	
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				3.8		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		3.4	4.2	0	
		V _{GS} = 4.5 V	I _D = 30 A		4.9	6.1	mΩ	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D	₎ = 15 A		58		S	
Gate Resistance	R_{G}	T _A = 25°0	0		1.0		Ω	
CHARGES AND CAPACITANCES								
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1683		pF	
Output Capacitance	C _{OSS}				841			
Reverse Transfer Capacitance	C _{RSS}				40			
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.023			
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			11.6		nC	
Threshold Gate Charge	Q _{G(TH)}				2.6			
Gate-to-Source Charge	Q _{GS}				4.7			
Gate-to-Drain Charge	Q_{GD}				4.0			
Gate Plateau Voltage	V_{GP}				3.1		V	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 30 A			26		nC	
SWITCHING CHARACTERISTICS (Note 6)	, ,							
Turn-On Delay Time	t _{d(ON)}				10			
Rise Time	t _r	Voc = 4.5 V Voc	s = 15 V		32		ns	
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 4.5 \text{ V}, V_{DS}$ $I_D = 15 \text{ A}, R_G = 10 \text{ A}$	$= 3.0 \Omega$		18			
Fall Time	t _f				5.0			
Turn-On Delay Time	t _{d(ON)}				8.0			
Rise Time	t _r	V _{GS} = 10 V, V _{DS}	. – 15 V		28		ns	
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 \text{ A}, R_G = 10 \text{ A}$	$= 3.0 \Omega$		24			
Fall Time	t _f				3.0		1	
DRAIN-SOURCE DIODE CHARACTERISTIC					<u> </u>	<u> </u>	1	
Forward Diode Voltage	V_{SD}	Voo - 0 V	T _J = 25°C		0.8	1.1		
		$V_{GS} = 0 \text{ V},$ $I_{S} = 10 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$			0.63		-	
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dlS/dt = 100 A/μs, l _S = 30 A			34			
Charge Time	ta				17		ns	
Discharge Time	t _b				17			
Reverse Recovery Charge	Q _{RR}				22		nC	
	~nn				1			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$. 6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



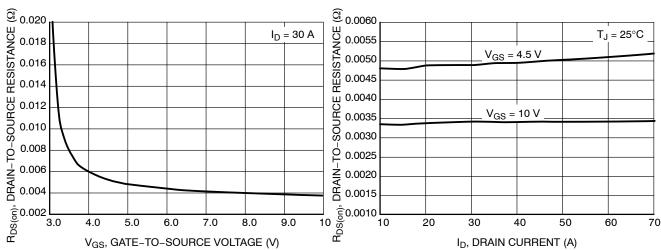


Figure 3. On-Resistance vs. V_{GS}

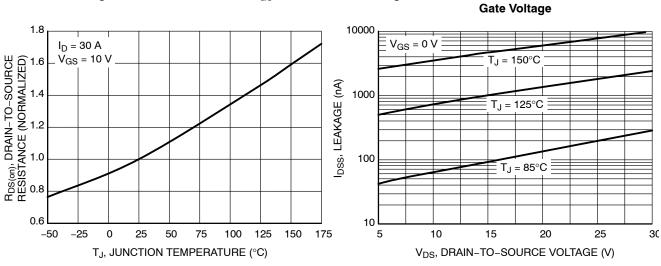


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

Figure 4. On-Resistance vs. Drain Current and

TYPICAL CHARACTERISTICS

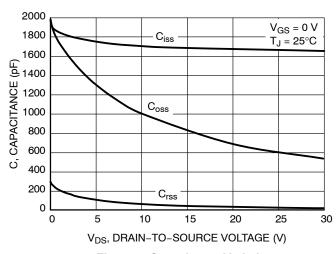


Figure 7. Capacitance Variation

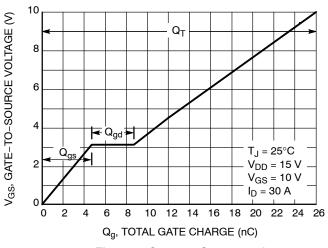


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

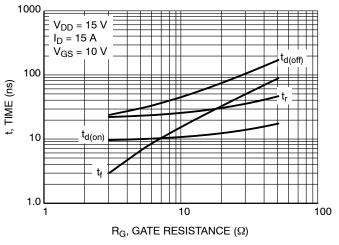


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

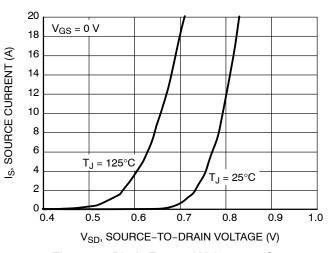


Figure 10. Diode Forward Voltage vs. Current

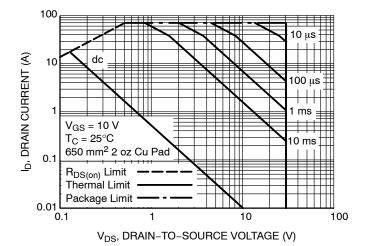


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

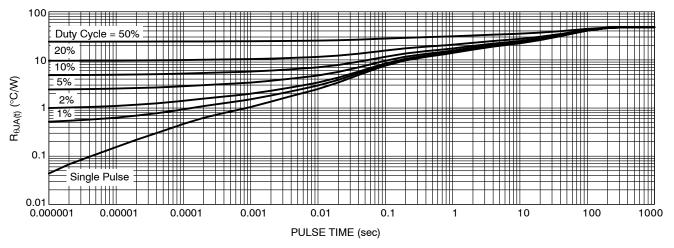


Figure 12. Thermal Response

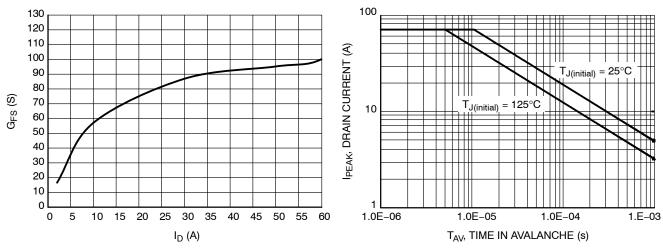


Figure 13. G_{FS} vs. I_D

Figure 14. Avalanche Characteristics

ORDERING INFORMATION

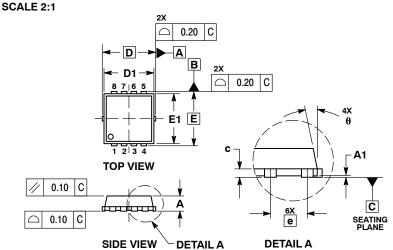
Device	Package	Shipping [†]
NVTFS4C06NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C06NWFTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C06NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel
NVTFS4C06NWFTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

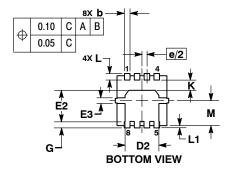
DATE 23 APR 2012



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
 PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0	.130 BSC	;	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E	3.30 BSC			0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			(0.026 BS	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



GENERIC MARKING DIAGRAM*

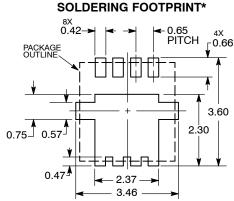


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON30561E	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	WDFN8 3.3X3.3. 0.65P		PAGE 1 OF 1		

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative